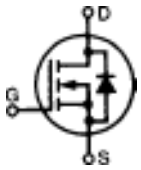
IXYS

MegaMOS™FET

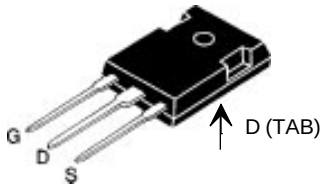
N-Channel Enhancement Mode

	V_{DSS}	I_{D25}	$R_{DS(on)}$
IXTH/IXTM 35 N30	**300 V**	**35 A**	**0.10 Ω**
IXTH 40 N30	**300 V**	**40 A**	**0.085 Ω**
IXTM 40 N30	**300 V**	**40 A**	**0.088 Ω**

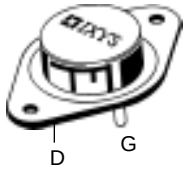


Symbol	Test Conditions		Maximum Ratings	
V_{DSS}	T_J = 25°C to 150°C		300	V
V_{DGR}	T_J = 25°C to 150°C; R_{GS} = 1 MΩ		300	V
V_{GS}	Continuous		±20	V
V_{GSM}	Transient		±30	V
I_{D25}	T_C = 25°C	35N30	35	A
		40N30	40	A
I_{DM}	T_C = 25°C, pulse width limited by T_{JM}	35N30	140	A
		40N30	160	A
P_D	T_C = 25°C		300	W
T_J			-55 ... +150	°C
T_{JM}			150	°C
T_{stg}			-55 ... +150	°C
M_d	Mounting torque		1.13/10	Nm/lb.in.
Weight			TO-204 = 18 g, TO-247 = 6 g	
Maximum lead temperature for soldering 1.6 mm (0.062 in.) from case for 10 s			300	°C

TO-247 AD (IXTH)



TO-204 AE (IXTM)



G = Gate, D = Drain,
S = Source, TAB = Drain

Symbol	Test Conditions		Characteristic Values (T_J = 25°C, unless otherwise specified) min.	typ.	max.	
V_{DSS}	V_{GS} = 0 V, I_D = 250 µA		300			V
$V_{GS(th)}$	V_{DS} = V_{GS}, I_D = 250 µA		2		4	V
I_{GSS}	V_{GS} = ±20 V_{DC}, V_{DS} = 0				±100	nA
I_{DSS}	V_{DS} = 0.8 • V_{DSS}	T_J = 25°C			200	µA
	V_{GS} = 0 V	T_J = 125°C			1	mA
$R_{DS(on)}$	V_{GS} = 10 V, I_D = 0.5 I_{D25}	IXTH/IXTM35N30			0.10	Ω
		IXTH40N30			0.085	Ω
		IXTM40N30			0.088	Ω
	Pulse test, t ≤ 300 µs, duty cycle d ≤ 2 %					

Features

- International standard packages
- Low $R_{DS\ (on)}$ HDMOS™ process
- Rugged polysilicon gate cell structure
- Low package inductance (< 5 nH)
  - easy to drive and to protect
- Fast switching times

Applications

- Switch-mode and resonant-mode power supplies
- Motor controls
- Uninterruptible Power Supplies (UPS)
- DC choppers

Advantages

- Easy to mount with 1 screw (TO-247) (isolated mounting screw hole)
- Space savings
- High power density

91535E(5/96)

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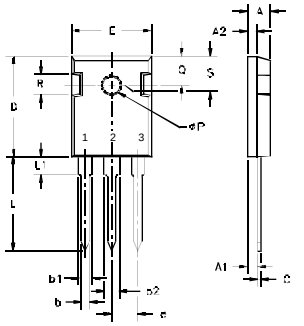
Symbol	Test Conditions	Characteristic Values (T_J = 25°C, unless otherwise specified) min.	typ.	max.	
g_{fs}	V_{DS} = 10 V; I_D = 0.5 • I_{D25}, pulse test	22	25		S
C_{iss}	V_{GS} = 0 V, V_{DS} = 25 V, f = 1 MHz		4600		pF
C_{oss}			650		pF
C_{rss}			240		pF
$t_{d(on)}$	V_{GS} = 10 V, V_{DS} = 0.5 • V_{DSS}, I_D = 0.5 I_{D25} R_G = 2 Ω, (External)		24	30	ns
t_r			40	90	ns
$t_{d(off)}$			75	100	ns
t_f			40	90	ns
$Q_{g(on)}$	V_{GS} = 10 V, V_{DS} = 0.5 • V_{DSS}, I_D = 0.5 I_{D25}		190	220	nC
Q_{gs}			28	50	nC
Q_{gd}			85	105	nC
R_{thJC}				0.42	K/W
R_{thCK}			0.25		K/W

Source-Drain Diode

Symbol	Test Conditions		Characteristic Values (T_J = 25°C, unless otherwise specified) min.	typ.	max.	
I_S	V_{GS} = 0 V	35N30			35	A
		40N30			40	A
I_{SM}	Repetitive; pulse width limited by T_{JM}	35N30			140	A
		40N30			160	A
V_{SD}	I_F = I_S, V_{GS} = 0 V, Pulse test, t ≤ 300 µs, duty cycle d ≤ 2 %				1.5	V
t_{rr}	I_F = I_S, -di/dt = 100 A/µs, V_R = 100 V			400		ns

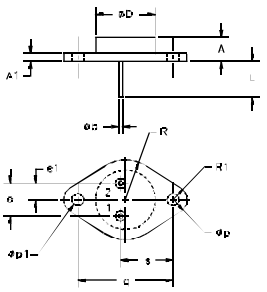
TO-247 AD (IXTH) Outline



Terminals: 1 - Gate 2 - Drain
3 - Source Tab - Drain

Dim.	Millimeter Min.	Max.	Inches Min.	Max.
A	4.7	5.3	.185	.209
A_1	2.2	2.54	.087	.102
A_2	2.2	2.6	.059	.098
b	1.0	1.4	.040	.055
b_1	1.65	2.13	.065	.084
b_2	2.87	3.12	.113	.123
C	.4	.8	.016	.031
D	20.80	21.46	.819	.845
E	15.75	16.26	.610	.640
e	5.20	5.72	0.205	0.225
L	19.81	20.32	.780	.800
L1		4.50		.177
∅P	3.55	3.65	.140	.144
Q	5.89	6.40	0.232	0.252
R	4.32	5.49	.170	.216
S	6.15 BSC		242 BSC	

TO-204AE (IXTM) Outline



Pins 1 - Gate 2 - Source
Case - Drain

Dim.	Millimeter Min.	Max.	Inches Min.	Max.
A	6.4	11.4	.250	.450
A1	1.53	3.42	.060	.135
∅b	1.45	1.60	.057	.063
∅D		22.22		.875
e	10.67	11.17	.420	.440
e1	5.21	5.71	.205	.225
L	11.18	12.19	.440	.480
∅p	3.84	4.19	.151	.165
∅p1	3.84	4.19	.151	.165
q	30.15 BSC		1.187 BSC	
R	12.58	13.33	.495	.525
R1	3.33	4.77	.131	.188
s	16.64	17.14	.655	.675

Fig. 1 Output Characteristics

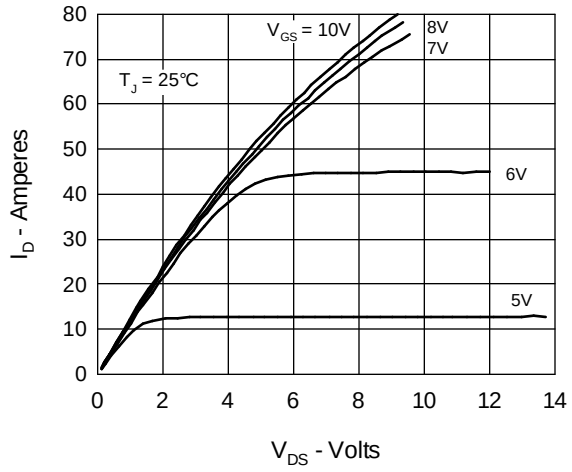


Fig. 2 Input Admittance

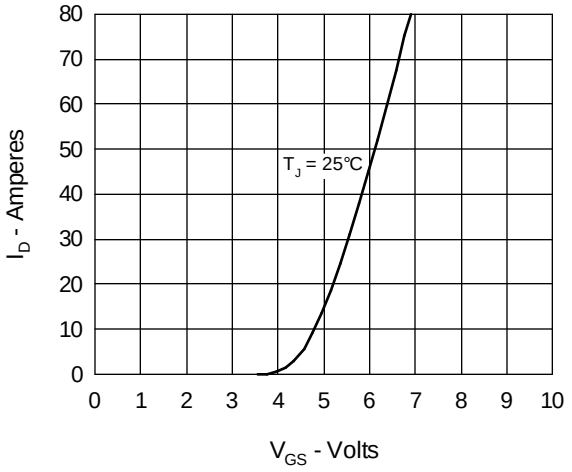


Fig. 3 $R_{DS(on)}$ vs. Drain Current

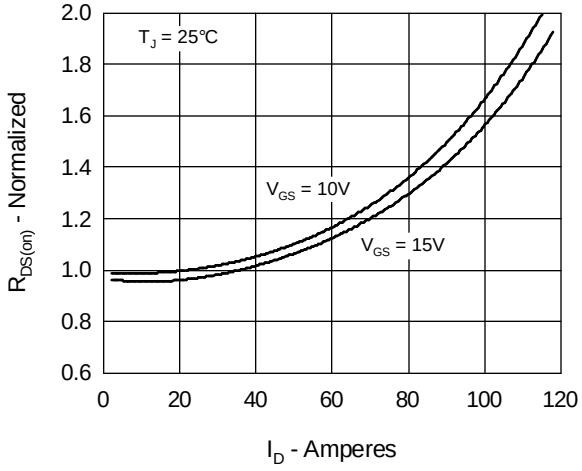


Fig. 4 Temperature Dependence of Drain to Source Resistance

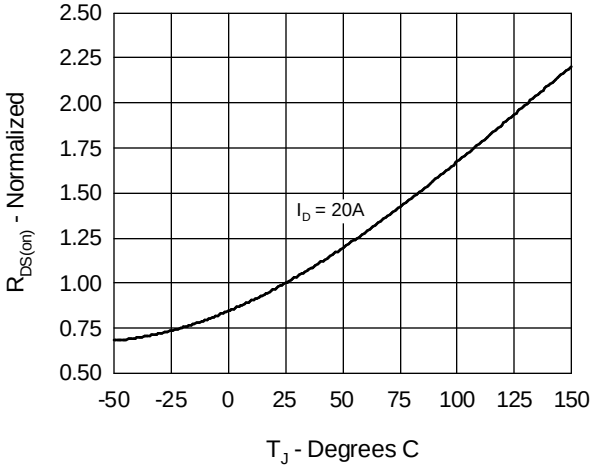


Fig. 5 Drain Current vs. Case Temperature

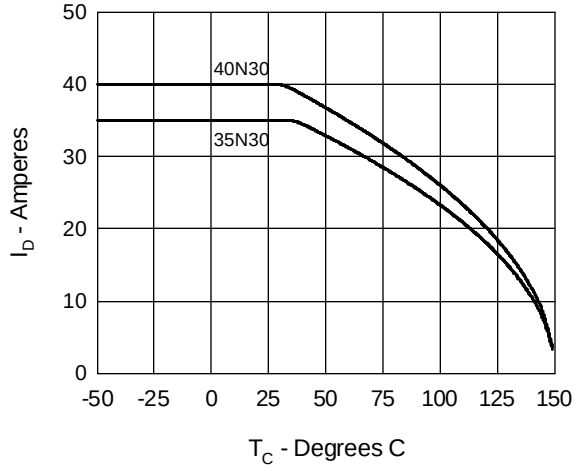


Fig. 6 Temperature Dependence of Breakdown and Threshold Voltage

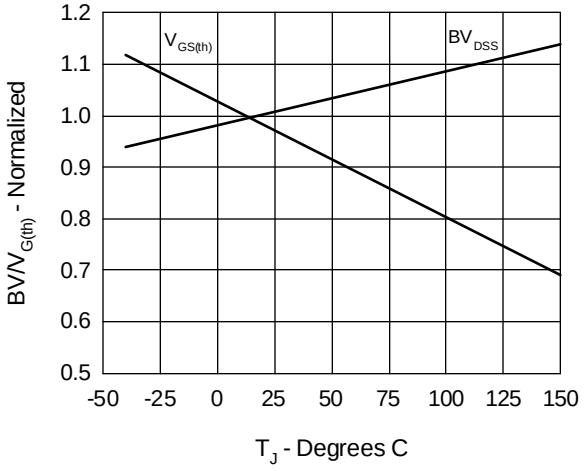


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Fig.7 Gate Charge Characteristic Curve

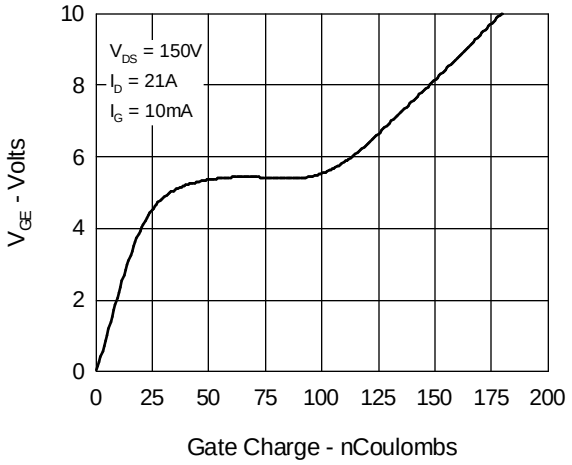

Fig.8 Forward Bias Safe Operating Area

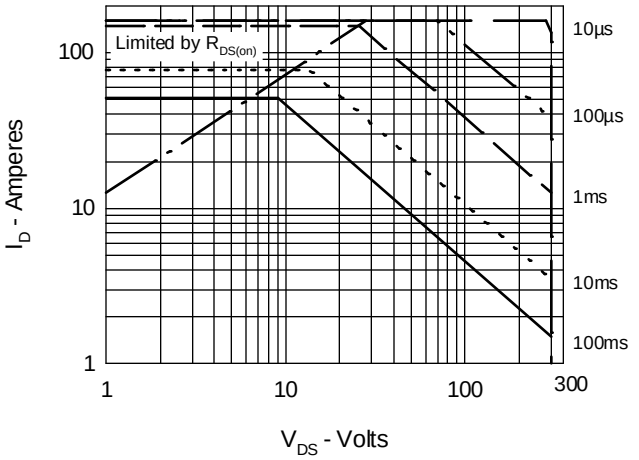

Fig.9 Capacitance Curves

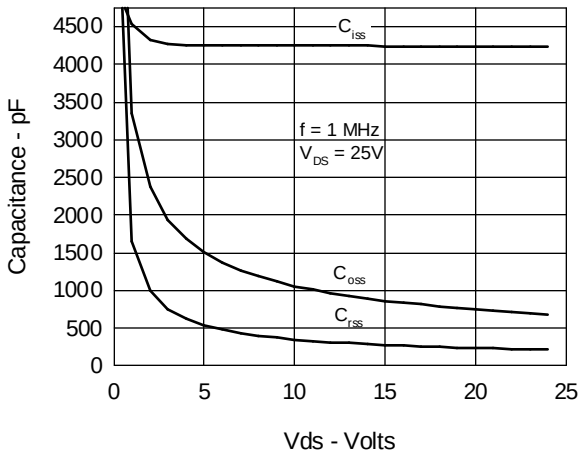

Fig.10 Source Current vs. Source to Drain Voltage

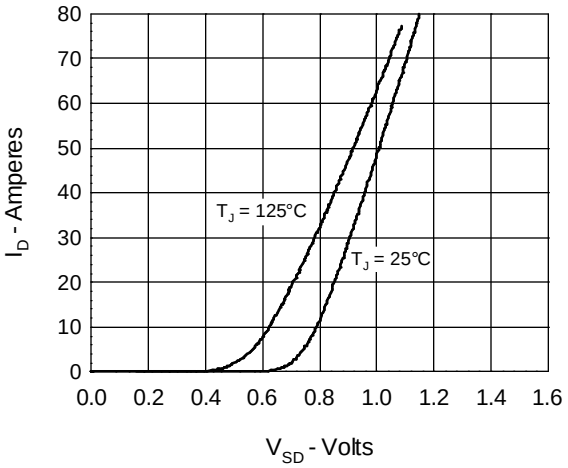

Fig.11 Transient Thermal Impedance